

Notice of References Cited	Application/Control No. 10/055,088	Applicant(s)/Patent Under Reexamination SAGATELIAN ET AL.	
	Examiner Cynthia Britt	Art Unit 2133	Page 1 of 1

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	B	US-6,557,132	04-2003	Gangl et al.	714/736
	C	US-5,727,000	03-1998	Pizzica, Stephen V.	714/737
	D	US-4,503,536	03-1985	Panzer, Gary W.	714/732
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.